

**Search Notes**

Application/Control No.

10/631,057

Examiner

Quoc A. Tran

Applicant(s)/Patent under  
Reexamination

DINH ET AL.

Art Unit

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	501.1	9/28/2005	
455	412.1	9/28/2005	
707	102	9/28/2005	
715	517	1/24/2006	
707	3	1/24/2006	
709	218	8/12/2006	
348	231.09	8/12/2006	

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	9/28/2005	
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) see Search Histoty Printout	9/28/2005	
NPL IEEE DataBase see Search History Printout	9/28/2005	
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) see Search Histoty Printout	1/24/2006	
ACM DataBase see Search History Printout	1/24/2006	
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) see Search Histoty Printout	8/12/2006	
ACM DataBase see Search History Printout	8/12/2006	